

STS12NH3LL N-CHANNEL 30 V - 0.008 Ω - 12 A SO-8

PRODUCT PREVIEW

ULTRA LOW GATE CHARGE STripFET[™] MOSFET

Table 1: General Features

TYPE	V _{DSS}	R _{DS(on)}	Ι _D
STS12NH3LL	30 V	< 0.0105 Ω	12 A

- TYPICAL R_{DS}(on) = 0.008 Ω @ 10V
- OPTIMAL R_{DS}(on) x Qg TRADE-OFF @ 4.5 V
- SWITCHING LOSSES REDUCED
- LOW THRESHOLD DEVICE
- LOW INPUT CAPACITANCE

DESCRIPTION

The STS12NH3LL is based on the latest generation of ST's proprietary "STripFET™" technology. An innovative layout enables the device to also exhibit extremely low gate charge for the most demanding requirements as high-side switch in highfrequency DC-DC converters. It's therefore ideal for high-density converters in Telecom and Computer applications.

APPLICATIONS

HIGH FREQUENCY DC-DC CONVERTERS FOR COMPUTER AND TELECOM

Figure 1: Package

Figure 2: Internal Schematic Diagram

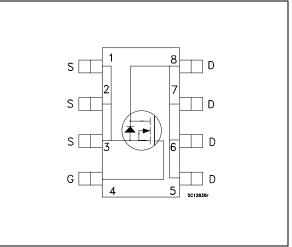


Table 2: Order Codes

Part Number	Marking	Package	Packaging
STS12NH3LL	S12NH3LL	SO-8	TAPE & REEL

Table 3: Absolute Maximum ratings

Symbol	Parameter	Value	Unit	
V _{DS}	Drain-source Voltage (V _{GS} = 0)	30	V	
V _{DGR}	Drain-gate Voltage (R _{GS} = 20 kΩ)	30	V	
V _{GS}	Gate-source Voltage	± 16	V	
I _D Drain Current (continuous) at T _C = 25°C		12	A	
I _D Drain Current (continuous) at T _C = 100°C		7.5	A	
I _{DM} (•)	Drain Current (pulsed)	48	A	
P _{tot}	Total Dissipation at T _C = 25°C	2.5	W	
T _{stg}	T _{stg} Storage Temperature		°C	
Тj	Max. Operating Junction Temperature	— 55 to 150		

(•) Pulse width limited by safe operating area

Table 4: Thermal Data

Rthj-amb (#)	Thermal Resistance Junction-ambient	50	°C/W		
(#) When Mounted on 1 inch ² FR-4 board, 2 oz Cu (t \leq 10 sec.)					

ELECTRICAL CHARACTERISTICS (T_{CASE} =25°C UNLESS OTHERWISE SPECIFIED)

Table 5: On /Off

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_{D} = 250 \ \mu A, \ V_{GS} = 0$	30			V
IDSS	Zero Gate Voltage Drain Current (V _{GS} = 0)	V_{DS} = Max Rating V_{DS} = Max Rating, T _C = 125°C			1 10	μA μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 16 V			± 100	nA
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	1			V
R _{DS(on)}	Static Drain-source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 6 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 6 \text{ A}$		0.008 0.010	0.0105 0.013	Ω Ω

Table 6: Dynamic

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (1)	Forward Transconductance	V _{DS} = 15V, I _D = 6 A		TBD		S
Ciss	Input Capacitance	V _{DS} = 25V, f= 1 MHz, V _{GS} = 0		965		pF
Coss	Output Capacitance			285		pF
C _{rss}	Reverse Transfer Capacitance			38		pF

ELECTRICAL CHARACTERISTICS (CONTINUED)

Table 7: Switching On

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on Delay Time	V _{DD} = 15 V, I _D = 6 A		15		ns
t _r	Rise Time	$R_G = 4.7\Omega$, $V_{GS} = 4.5V$ (see Figure 3)		32		ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V_{DD} = 15V, I _D = 12 A, V _{GS} = 4.5 V (see Figure 5)		9 3.7 3	12	nC nC nC

Table 8: Switching Off

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(off)} t _f	Turn-off-Delay Time Fall Time	V_{DD} = 15 V, I _D = 6 A, R _G = 4.7 Ω , V _{GS} = 4.5 V (see Figure 3)		18 8.5		ns ns

Table 9: Source Drain Diode

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} (2)	Source-drain Current Source-drain Current (pulsed)				12 48	A A
V _{SD}	Forward On Voltage	$I_{SD} = 12 \text{ A}, V_{GS} = 0$			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 12 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$ $V_{DD} = 20\text{V}, \text{ T}_{j} = 150^{\circ}\text{C}$ (see Figure 4)		24 17.4 1.45		ns nC A

Figure 3: Switching Times Test Circuit For Resistive Load

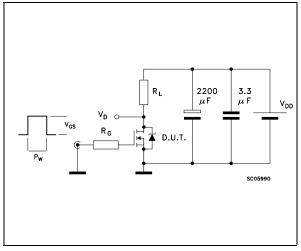


Figure 4: Test Circuit For Diode Recovery Times

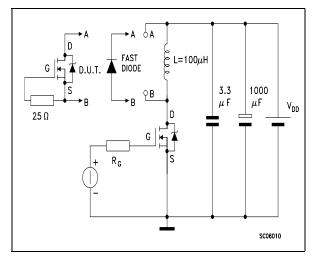
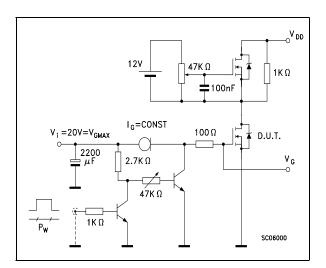


Figure 5: Gate Charge Test Circuit



DIM		mm.			inch	
DIM.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.
А			1.75			0.068
a1	0.1		0.25	0.003		0.009
a2			1.65			0.064
a3	0.65		0.85	0.025		0.033
b	0.35		0.48	0.013		0.018
b1	0.19		0.25	0.007		0.010
С	0.25		0.5	0.010		0.019
c1		•	45	(typ.)	•	
D	4.8		5.0	0.188		0.196
Е	5.8		6.2	0.228		0.244
е		1.27			0.050	
e3		3.81			0.150	
F	3.8		4.0	0.14		0.157
L	0.4		1.27	0.015		0.050
М			0.6			0.023
S		1	8 (r	nax.)	•	



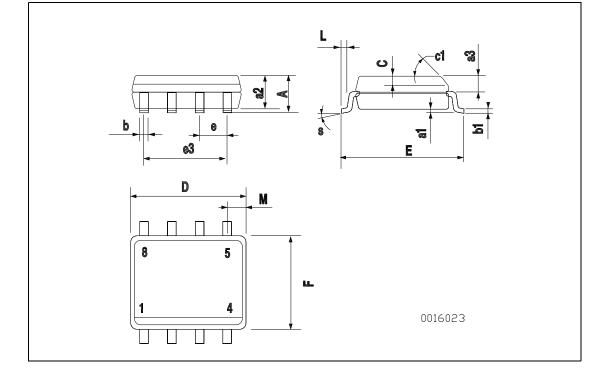


Table 10: Revision History

Date	Revision	Description of Changes
21-July-2004	3	The Rds(on) value changed (see table5).
		New stylesheet

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